## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | JOHANSEN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

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	U	Definition of diffraction, Merriam-Webster Online Dictionary, Tenth Edition
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